

# RF Measurements and Documentation for the Industrial Fabrication of SC Cavities.

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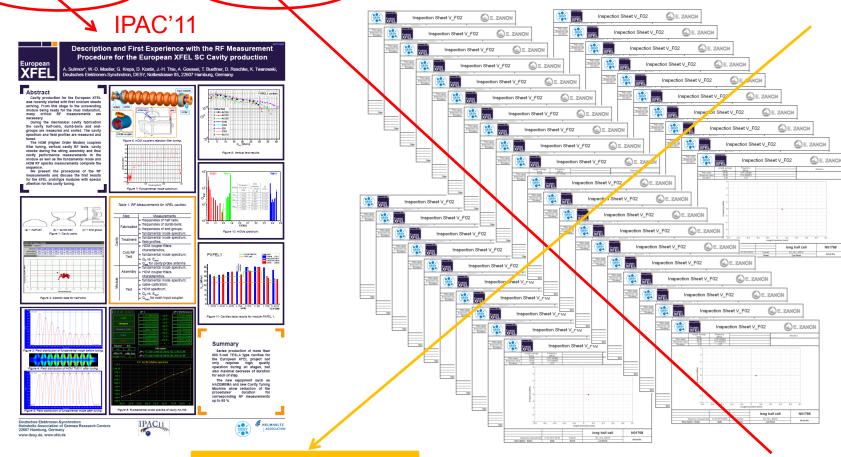




### XFEL RF aspects of quality control for XFEL cavities



RF Measurements and Occurrentation for the Industrial Fabrication of SC Cavities



RF aspects of quality control for XFEL serial cavities.







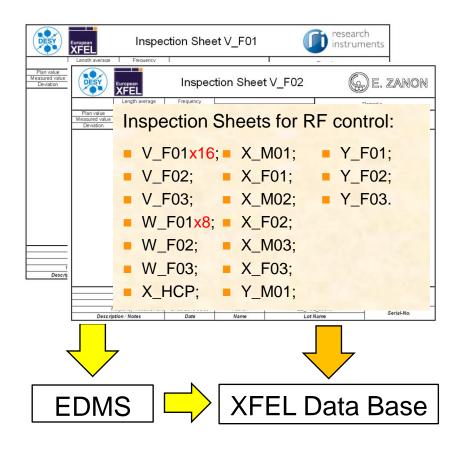


### Production Sequence



#### **Production sequence:**

- Cavity parts fabrication,
- Cavity welding,
- Cavity tuning,
- Welding in helium tank (HT),
- Pressure test (PT),
- Cavity transport.







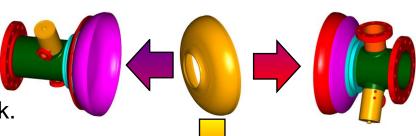
### Cavity parts fabrication



#### **Cavity parts fabrication:**

- Shape control for half cells (HC), end groups (EG) and dumb-bells (DB);
- DBs asymmetry control;
- Calculation of optimal parts lengths;
- DBs sorting in cavity;
- Estimation of cavity length in helium tank.









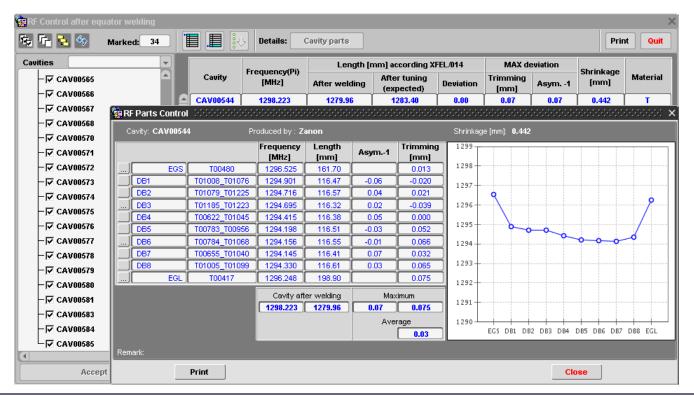


### FEL Cavity Welding (Acceptance Level 1)



#### After cavity welding:

- Measure the pi-mode frequency and cavity length;
- Control the welding parameters (shrinkage and deformation);
- Calculated the cavity length in helium tank.











### XFEL Cavity Tuning

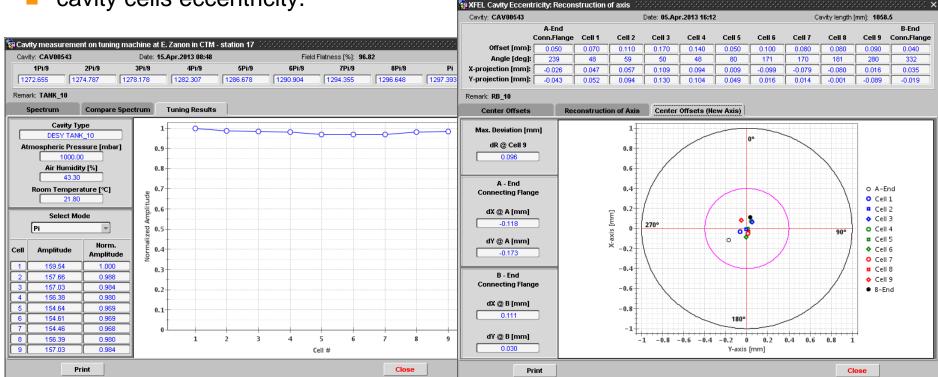


#### Values are controlled during cavity tuning:

- pi-mode frequency,
- field flatness (FF),
- cavity length,

cavity cells eccentricity.











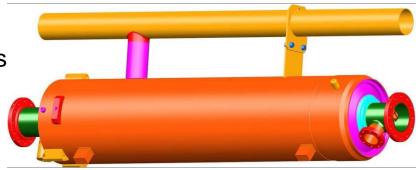
#### RF Measurements and Documentation for the Industrial Fabrication of SC Cavities

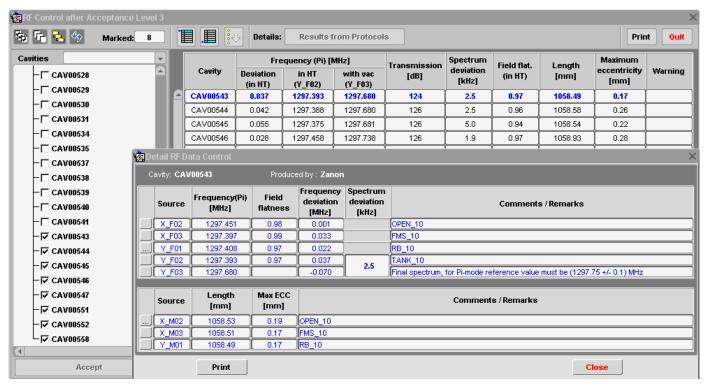
### Welding in Helium Tank and Pressure Test XFEL (Acceptance Level 2)



#### Welding in helium tank, pressure test:

- Control of pi-mode frequency during the rings with bellow and HT welding;
- Checking of RF parameters (Fpi, FF) before and after HT and PT.















### XFEL Cavity Transport (Acceptance Level 3)



### To estimate Field Flatness (FF) changes the two spectra have to be compared:

- Reference spectrum SP2 can be downloaded from XFEL DB (it's a spectrum with known value of FF<sup>ref</sup>)
- N = 9 number of cavity cells, measured spectrum SP1 = {f<sub>i</sub>}, SP2 = {F<sub>i</sub>}, where i = 1...N.
- Relative spectrum is calculated as:

$$RS = \{R_i\} = \{F_i/f_i - F_N/f_N\}, \text{ where } i = 1...N.$$

Linear Fit is calculated for relative spectrum:

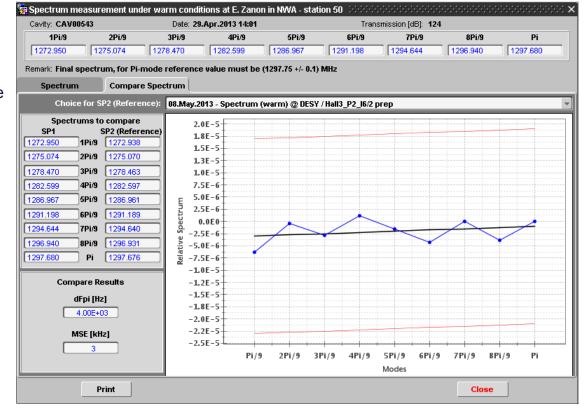
$$L = \{L_i\} = linear\_fit\{R_i\}, i = 1...N$$

Mean squared error iş çalculated as:

$$mse = \sum_{i=1}^{N} (R_i - L_i)^T / N$$

Mean spectrum frequency deviation is calculated as:

$$MSE[kHz] = \sqrt{mse} \times f_{\pi}^{op}, f_{\pi}^{op} = 1.3GHz$$





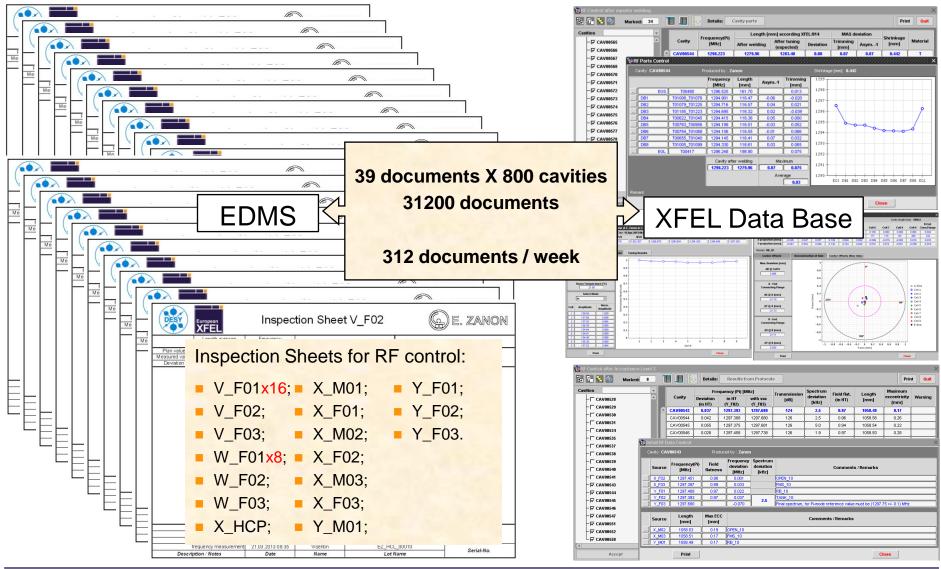






### XFEL Conclusion









### \_ Acknowledgements



## We appreciate:

- company E.Zanon for possibility to present the data.
- IPP DESY group for supporting the EDMS and data transfer.
- DESY Data Base Team for organizing the automation of data analysis.







### THANK YOU!



# Thank you all for attention!



